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# applied surface science

A journal devoted to applied physics
and chemistry of surfaces and interfaces

# APPLIED SURFACE SCIENCE

*A journal devoted to applied physics and chemistry of surfaces and interfaces*

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Atom scattering
Atomic and molecular beam studies
Atomic force microscopy
Atomic layer deposition
Augar electron spectroscopy

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Berillium
Biological materials
Bismath
Boron
Boron nitride

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Tungsten
Tunneling

Vanadium

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Work function

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X-ray diffractions
X-ray emission
X-ray fluorescence
X-ray magnetic circular dichroism
X-ray scattering
X-ray spectroscopy
Ytrium

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Zirconium

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